## Notice of References Cited Application/Control No. Applicant(s)/Patent Under Reexamination BIEDERMAN ET AL. Examiner Art Unit Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*	,	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2005/0084076	04-2005	Dhir et al.	379/055.1
*	В	US-2004/0076181	04-2004	Pantelias et al.	370/468
*	С	US-2003/0126428	07-2003	Liu et al.	713/151
*	D	US-6,973,566	12-2005	Smith et al.	713/151
*	E	US-5,689,568	11-1997	Laborde, Enrique	713/151
	F	US-	-		
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-		·	<u> </u>

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0		·			
	Р		_			
	Q					
	R	•				
	S					
	Т		,			

## **NON-PATENT DOCUMENTS**

*	<u> </u>	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	х	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.